## Notice of References Cited Application/Control No. 10/588,261 Examiner ADNAN BAIG Applicant(s)/Patent Under Reexamination YONEMOTO ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0225512	12-2003	Kim et al.	701/209
*	В	US-6,330,238	12-2001	Ooe, Kazuichi	370/390
	U	US-			
	ם	US-			
	ш	US-			
	F	US-			
	O	US-			
	Ι	US-			
	_	US-			
	٦	US-			
	K	US-			
	┙	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	W	
	×	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.